

# Arc Fault

## UL1699B Task Group 1

Marv Dargatz



## Problems to be tackled:

1. It was discovered that the old method of testing resulted in listed products that **did not detect some arcs** in real world conditions
2. And, some listed products suffered from unwanted **nuisance tripping**

## Objectives:

- Redefine test method and fixture  
*(progress summarized here)*
- Develop method to test unwanted tripping  
*(not addressed yet)*

## Guidelines

- Test method and setup must represent worst case real world conditions
- Must be agnostic to AFCI detection method
- Must be repeatable and consistent



## UL1699B Task Group 1

### Existing Arc Gap



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### Proposed Arc Gap



- More representative arc signature
- More repeatable

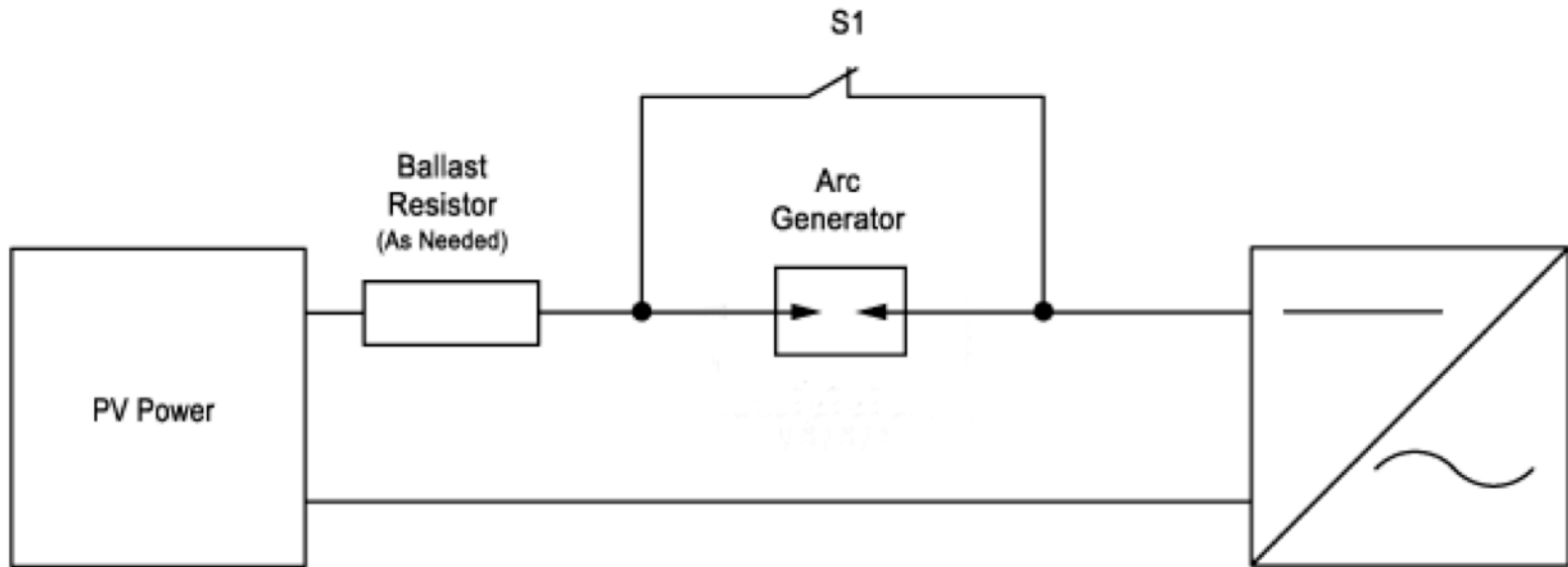


## Proposals

- Two test methods
  - Slow pull-apart – *to simulate separation of conductors/ connectors over time*
  - Step apart – *to measure tripping times*
- Two arc locations
  - Next to AFCI detector - *legacy*
  - Middle of DC source – *worst case*



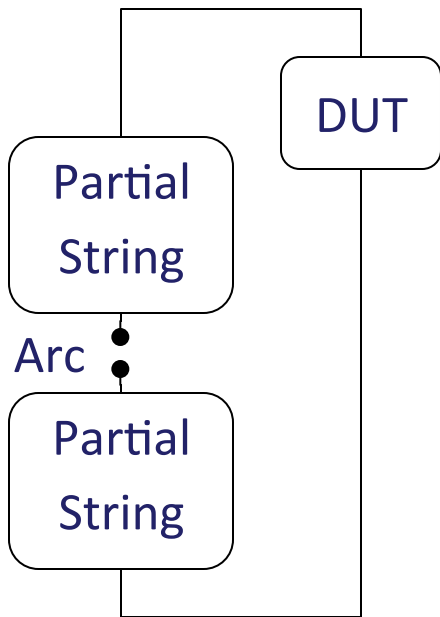
## Existing Test Setup



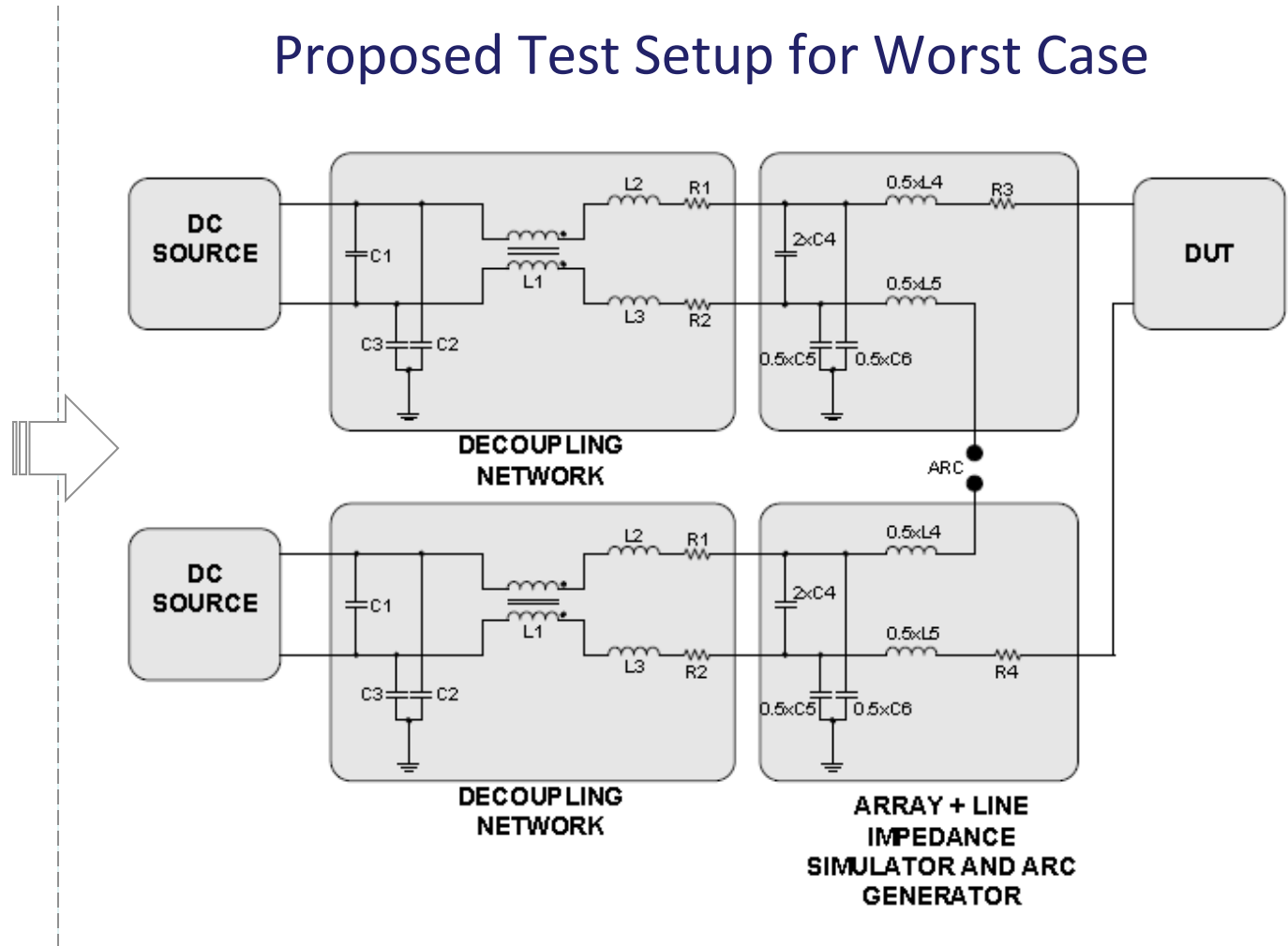
- Arc generated close to the AFCI detector – not worst case



### Concept



### Proposed Test Setup for Worst Case





# Questions?

